

Gate Driver for Mobility and Power Tool

# 4.5 V to 60 V, Three-phase Brushless DC Motor Gate Driver

## BD67870MWV-Z

### General Description

The BD67870MWV-Z is a gate driver IC designed for three-phase brushless DC motor applications. The BD67870MWV-Z can drive three half-bridges consisting of six N-Channel power MOSFETs up to 60 V.

### Features

- Wide 4.5 V to 60 V Input Voltage Range
- Bootstrap Gate Driver with Current Source Circuit for 100 % Duty Cycle Operation and High-impedance (Hi-Z) State with Trickle Charge Pump
- Super Low  $I_{VCCQ}$  ( $< 1 \mu A$  at Sleep Mode)
- Thermal Shutdown, Input  $V_{CC}$  and Gate Driver  $V_{REG}$  UVLO Protection
- Adjustable Dead Time Control by External Resistor from 10 ns to 3000 ns
- 6x PWM Mode (Input Logic)

### Applications

- Three-Phase, Brushless, DC Motors
- Permanent Magnet Synchronous Motors
- Power Tools
- E-Bikes, Mobility

### Typical Application Circuits

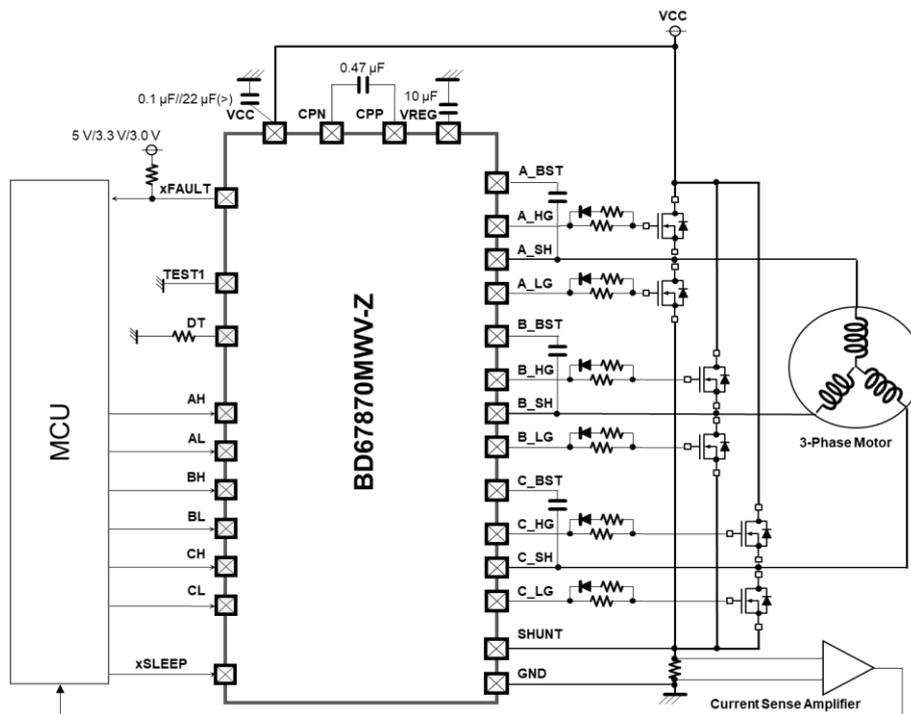


Figure 1. Application Example

### Key Specifications

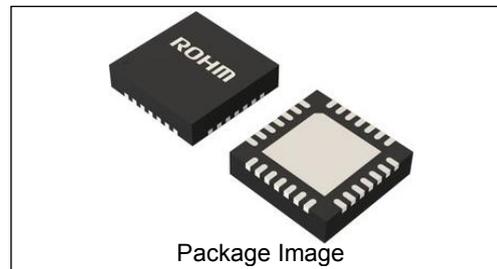
■ $V_{CC}$ Range	4.5 V to 60 V
■ Gate Driver Strength (Source)	0.5 A (Typ)
■ Gate Driver Strength (Sink)	1.0 A (Typ)
■ $V_{CC}$ UVLO	3.8 V (Typ)
■ Maximum Junction Temperature	+150 °C

### Package

UQFN28AV040A

W (Typ) x D (Typ) x H (Max)

4.0 mm x 4.0 mm x 1.0 mm



Package Image

○Product structure : Silicon integrated circuit ○This product has no designed protection against radioactive rays.



## Pin Descriptions

Pin No.	Pin Name	Function
1	VCC	Input supply voltage. Bypass VCC to ground with a ceramic and electrolytic capacitor. 0.1 $\mu$ F ceramic capacitor and 22 $\mu$ F or more electrolytic capacitor are recommended. Apply the same voltage as the drain voltage of the High-side MOSFET
2	CPP	Charge pump capacitor. Connect a ceramic capacitor between CPP and CPN.
3	CPN	Ceramic capacitor is recommended. See component selection guide for recommended value.
4	VREG	Gate drive supply output. Connect a ceramic capacitor between VREG and ground.
5	A_BST	Bootstrap phase A. Connect a ceramic capacitor to A_SH. See component selection guide for recommended value.
6	A_SH	High-side source connection phase A.
7	A_HG	High-side gate drive output phase A.
8	A_LG	Low-side gate driver output phase A.
9	B_BST	Bootstrap phase B. Connect a ceramic capacitor to B_SH. See component selection guide for recommended value.
10	B_SH	High-side source connection phase B.
11	B_HG	High-side gate driver output phase B.
12	B_LG	Low-side gate drive output phase B.
13	C_BST	Bootstrap phase C. Connect a ceramic capacitor to C_SH. See component selection guide for recommended value.
14	C_SH	High-side source connection phase C.
15	C_HG	High-side gate driver output phase C.
16	C_LG	Low-side gate driver output phase C.
17	SHUNT	Return path for low-side driver.
18	CH	Phase C high-side input.
19	BH	Phase B high-side input.
20	AH	Phase A high-side input.
21	CL	Phase C low-side input.
22	BL	Phase B low-side input.
23	AL	Phase A low-side input.
24	xFAULT	Open drain fault indicator pin.
25	xSLEEP	When the xSLEEP pin is driven to ground, the gate driver device is put into sleep mode
26	TEST1	Test output pin for internal use. For normal application this pin connect to GND or pull up to VREG with 100 k $\Omega$ .
27	DT	Pin to connect external dead time adjustment resistor. See operation section for calculation of resistor value.
28	GND	Ground.
-	EXP-PAD	Connect exposed pad to GND

Block Diagram

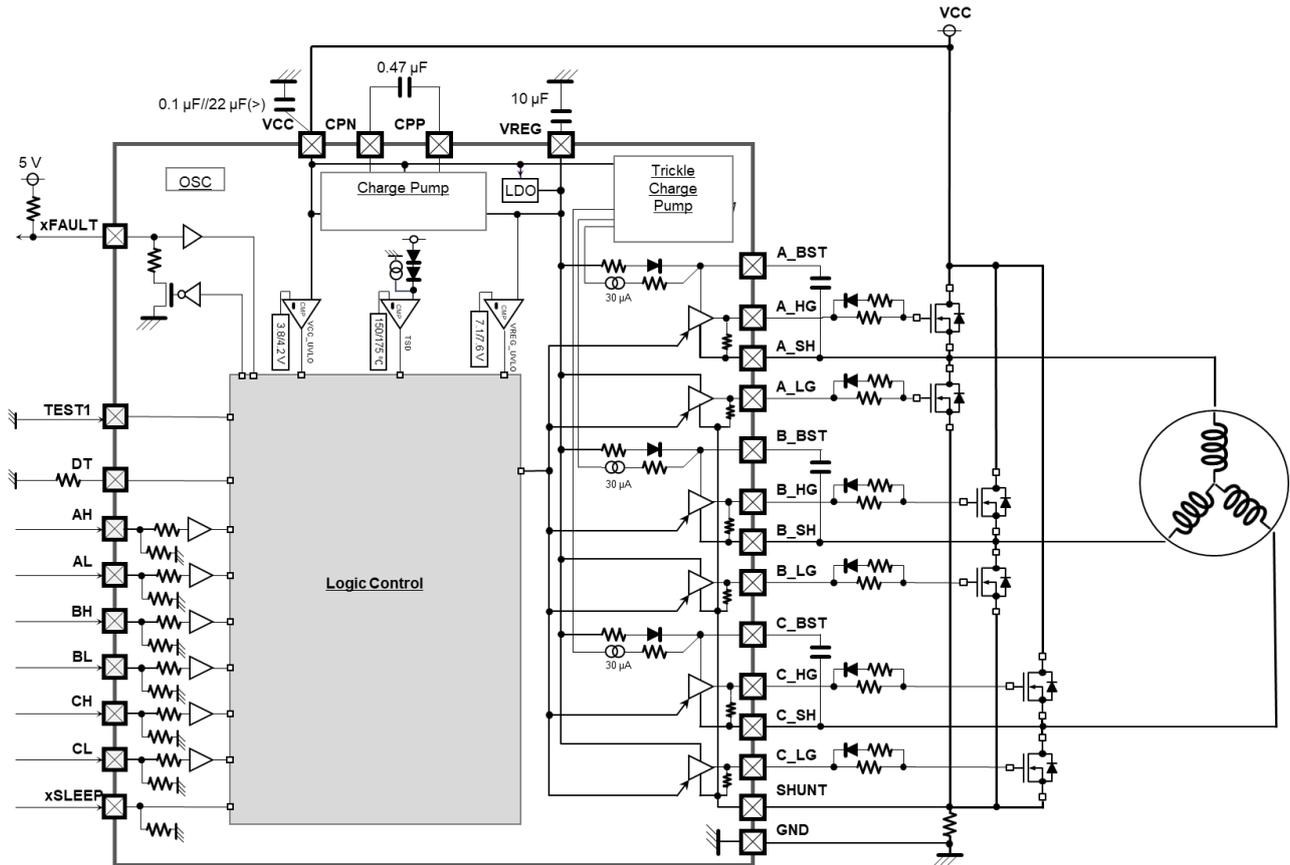


Figure 3. Functional Block Diagram

**Absolute Maximum Ratings** (respect to GND unless otherwise noted.)

Parameter	Symbol	Rating	Unit
Input Voltage	V <sub>CC</sub>	-0.3 to +65.0	V
CPP Pin Input Voltage	V <sub>CPP</sub>	-0.3 to +15.5	V
CPN Pin Input Voltage	V <sub>CPN</sub>	-0.3 to +15.5	V
VREG Pin Input Voltage	V <sub>REG</sub>	-0.3 to +15.0	V
*_BST – *_SH (* = A, B, C) (Note 1)	V <sub>BST-SH</sub>	-0.3 to +15.0	V
*_BST – *_HG (* = A, B, C) (Note 1)	V <sub>BST-HG</sub>	-0.3 to +15.0	V
*_BST (* = A, B, C) (Note 1)	V <sub>BST</sub>	-0.3 to +80.0	V
*_HG (* = A, B, C) (Note 1) (Note 2)	V <sub>HG</sub>	-8.0 to +80.0	V
*_LG (* = A, B, C) (Note 1)	V <sub>LG</sub>	-0.3 to +15.0	V
*_SH (* = A, B, C) (Note 1) (Note 2)	V <sub>SH</sub>	-8.0 to +65.0	V
SHUNT Pin Input Voltage	V <sub>SHUNT</sub>	-1.0 to +1.0	V
DT Pin Input Voltage	V <sub>DT</sub>	-0.3 to +2.0	V
xSLEEP Pin Input Voltage	V <sub>xSLEEP</sub>	-0.3 to +6.5	V
TEST1 Pin Input Voltage	V <sub>TEST1</sub>	-0.3 to +6.5	V
Logic Input Voltage	V <sub>IN</sub>	-0.3 to +6.5	V
xFAULT Pullup Voltage	V <sub>O</sub>	-0.3 to +6.5	V
xFAULT Sink Performance	I <sub>O</sub>	5	mA
Storage Temperature Range	T <sub>stg</sub>	-55 to +150	°C
Maximum Junction Temperature	T <sub>jmax</sub>	150	°C

(Note 1) A, B and C is one of 3 outputs name

(Note 2) Acceptable time duration of Negative Voltage depends on external capacitor value placed between \*\_BST and \*\_SH. (V\*\_BST – V\*\_SH must be ≤15 V). As a reference, it would be covered over 2 μs if the capacitor value is 1 μF

**Caution 1:** Operating the IC over the absolute maximum ratings may damage the IC. The damage can either be a short circuit between pins or an open circuit between pins and the internal circuitry. Therefore, it is important to consider circuit protection measures, such as adding a fuse, in case the IC is operated over the absolute maximum ratings.

**Caution 2:** Should by any chance the maximum junction temperature rating be exceeded the rise in temperature of the chip may result in deterioration of the properties of the chip. In case of exceeding this absolute maximum rating, design a PCB with thermal resistance taken into consideration by increasing board size and copper area so as not to exceed the maximum junction temperature rating.

**Recommended Operating Conditions**

Parameter	Symbol	Min	Typ	Max	Unit
Input Voltage	V <sub>CC</sub>	4.5	-	60	V
Input Voltage Ramp Rate at Power Up	V <sub>CC_RAMP_UP</sub>	-	-	30.0	V/μs
Input Voltage Ramp Rate during Operation	V <sub>CC_RAMP_ope</sub>	-	-	4.0	V/μs
Slew Rate on *_SH Pins	V <sub>SH_SR</sub>	-	-	4.0	V/ns
DT Pin Input Voltage	V <sub>DT</sub>	0.0	-	1.0	V
xSLEEP Pin Input Voltage	V <sub>xSLEEP</sub>	0.0	-	5.5	V
TEST1 Pin Input Voltage	V <sub>TEST1</sub>	0.0	-	5.5	V
xFAULT Pullup Voltage	V <sub>O</sub>	0.0	-	5.5	V
Logic Input Voltage	V <sub>IN</sub>	0.0	-	5.5	V
Minimum Pulse Input Width of xSLEEP	T <sub>w</sub>	20	-	-	μs
Operating Temperature	T <sub>opr</sub>	-40	-	+125	°C
Operating Junction Temperature	T <sub>j</sub>	-40	-	+150	°C

**Thermal Resistance** (Note 3)

Parameter	Symbol	Thermal Resistance (Typ)		Unit
		1s <sup>(Note 5)</sup>	2s2p <sup>(Note 6)</sup>	
UQFN28AV040A				
Junction to Ambient	$\theta_{JA}$	120.3	47.6	°C/W
Junction to Top Characterization Parameter <sup>(Note 4)</sup>	$\Psi_{JT}$	19.9	12.3	°C/W

(Note 3) Based on JESD51-2A (Still-Air).

(Note 4) The thermal characterization parameter to report the difference between junction temperature and the temperature at the top center of the outside surface of the component package.

(Note 5) Using a PCB board based on JESD51-3.

(Note 6) Using a PCB board based on JESD51-5, 7.

Layer Number of Measurement Board	Material	Board Size
Single	FR-4	114.3 mm x 76.2 mm x 1.57 mmt

Top	
Copper Pattern	Thickness
Footprints and Traces	70 $\mu$ m

Layer Number of Measurement Board	Material	Board Size	Thermal Via <sup>(Note 7)</sup>	
			Pitch	Diameter
4 Layers	FR-4	114.3 mm x 76.2 mm x 1.6 mmt	1.20 mm	$\Phi$ 0.30 mm

Top		2 Internal Layers		Bottom	
Copper Pattern	Thickness	Copper Pattern	Thickness	Copper Pattern	Thickness
Footprints and Traces	70 $\mu$ m	74.2 mm x 74.2 mm	35 $\mu$ m	74.2 mm x 74.2 mm	70 $\mu$ m

(Note 7) This thermal via connect with the copper pattern of layers 1,2, and 4. The placement and dimensions obey a land pattern.

Electrical Characteristics (Unless otherwise specified  $V_{CC} = 24\text{ V}$ ,  $T_{op} = 25\text{ °C}$ ) (Note 8)

Parameter	Symbol	Min	Typ	Max	Unit	Condition
Power Supply						
Input Supply Voltage	$V_{CC}$	4.5	-	60	V	
Quiescent Current	$I_{VCC}$	1.8	2.8	3.5	mA	$V_{XSLEEP} \geq 2.0\text{ V}$ (active mode) (A_SH, B_SH, C_SH) = (H, Z, L) $R_{DT} = 100\text{ k}\Omega$
	$I_{VCC2}$	-	2.8	-	mA	$V_{XSLEEP} \geq 2.0\text{ V}$ (active mode) xH, xL is 20 kHz Switching $R_{DT} = 100\text{ k}\Omega$
	$I_{VCCQ}$	-	-	1	$\mu\text{A}$	$V_{XSLEEP} \leq 0.6\text{ V}$ (sleep mode)
Control Logic						
Input Logic Low Threshold	$V_{IL}$	-	-	0.8	V	
Input Logic High Threshold	$V_{IH}$	2.0	-	-	V	
xSLEEP Input Low Threshold	$V_{IL\_XSLEEP}$	-	-	0.6	V	
xSLEEP Input High Threshold	$V_{IH\_XSLEEP}$	2.0	-	-	V	
Logic Input Current	$I_{IN(H)}$	3	6	10	$\mu\text{A}$	$V_{IN} = 5.0\text{ V}$
	$I_{IN(L)}$	-10	+1	+10	$\mu\text{A}$	$V_{IN} = 0.8\text{ V}$
Internal Pull-down Resistance	$R_{PD}$	640	800	960	k $\Omega$	6 control pins
Fault Outputs (Open-Drain Outputs)						
Output Low Voltage	$V_{OL}$	-	-	0.5	V	$I_o = 5\text{ mA}$
Output High Leakage Current	$I_{OH}$	-	-	1	$\mu\text{A}$	$V_o = 3.3\text{ V}$
Protection Circuit						
$V_{CC}$ Voltage as OK to Active	$V_{CC\_GOOD}$	3.9	4.2	4.5	V	
$V_{CC}$ UVLO Detecting Voltage	$V_{CC\_NG}$	3.6	3.8	4.0	V	
$V_{CC}$ Hysteresis	$V_{CC\_HYS}$	0.2	0.4	0.6	V	
$V_{REG}$ Threshold	$V_{REG\_GOOD}$	7.2	7.6	8.0	V	
$V_{REG}$ UVLO Detecting Voltage	$V_{REG\_NG}$	6.7	7.1	7.5	V	
$V_{REG}$ Hysteresis	$V_{REG\_HYS}$	0.3	0.5	0.7	V	
TSD Detecting Temperature	$T_{TSDON}$	-	175	-	$^{\circ}\text{C}$	
TSD Temperature as OK to Active	$T_{TSDOFF}$	-	150	-	$^{\circ}\text{C}$	
TSD Hysteresis	$T_{TSDHYS}$	-	25	-	$^{\circ}\text{C}$	
$V_{REG}$ Start Up Delay	$t_{REG}$	-	850	-	$\mu\text{s}$	
Wake Up Time	$t_{WAKEUP}$	-	1	-	ms	$V_{XSLEEP} \geq 2.0\text{ V}$ (active mode)
Turn Off Time	$t_{SLEEP}$	-	4	-	$\mu\text{s}$	$V_{XSLEEP} \leq 0.6\text{ V}$ (sleep mode)

(Note 8) Voltage is measured from GND unless otherwise noted.

Electrical Characteristics - continued (Unless otherwise specified  $V_{CC} = 24\text{ V}$ ,  $T_{opr} = 25\text{ }^{\circ}\text{C}$ ) (Note 8)

Parameter	Symbol	Min	Typ	Max	Unit	Condition
Gate Drive						
Bootstrap Diode Forward Voltage	$V_{FB00T}$	-	-	0.9	V	$I_F = 5\text{ mA}$
$V_{REG}$ Output Voltage	$V_{REG}$	10.0	12.5	13.5	V	$V_{CC} = 6.25\text{ V to }60\text{ V}$
		$2 \times V_{CC} - 1$	-	$2 \times V_{CC}$		$V_{CC} = 4.5\text{ V to }6.25\text{ V}$
Gate Driver Strength (source)	$I_{SRC}$	-	0.5	-	A	Pulse width < 10 $\mu\text{s}$
Gate Driver Strength (sink)	$I_{SNK}$	-	1.0	-	A	Pulse width < 10 $\mu\text{s}$
HS Gate Drive Pull-up Resistance	$R_{HS-UP}$	2	5	8	$\Omega$	$I_D = 100\text{ mA}$
HS Gate Drive Pull-down Resistance	$R_{HS-DN}$	1.0	3.0	5.5	$\Omega$	$I_D = 100\text{ mA}$
HS Semiactive Pull-down Resistance	$R_{HS-PDN}$	-	-	16	k $\Omega$	*_HG to *_SH : $V_{GSHG} = 2\text{ V}$
LS Gate Drive Pull-up Resistance	$R_{LS-UP}$	2	5	8	$\Omega$	$I_D = 100\text{ mA}$
LS Gate Drive Pull-down Resistance	$R_{LS-DN}$	1.0	3.0	5.5	$\Omega$	$I_D = 100\text{ mA}$
LS Passive Pull-down Resistance	$R_{LS-PDN}$	-	590	-	k $\Omega$	
LS Automatic Turn-on Time	$t_{LS}$	-	0.5	-	$\mu\text{s}$	After $V_{REG} \geq V_{REG\_GOOD}$
Charge Pump Frequency	$f_{CP}$	-	110	-	kHz	
Turn On/Off Delay from 6inputs to 6outputs	$t_{RISE}$	-	25	60	ns	Rise Delay
	$t_{FALL}$	-	25	60	ns	Fall Delay
Matching Propagation Delay per Phase	$t_{PD\_MATCH}$	-	+/-4	-	ns	
Matching Propagation Delay per Phase to Phase	$t_{PD\_MATCH\_PP}$	-	+/-4	-	ns	
Maximum Frequency of 6inputs	$f_{MAX\_6IN}$	-	-	1000	kHz	$R_{DT} = 0\text{ }\Omega$
Minimum Pulse Width	$t_{MIN\_6IN}$	45	-	-	ns	$V_{CC} = 4.5\text{ V}$
Dead Time	$t_{DEAD}$	-	10	-	ns	$R_{DT} = 0\text{ }\Omega = \text{Tied to GND}$
		-	110	-	ns	$R_{DT} = 3.3\text{ k}\Omega$
		-	1800	-	ns	$R_{DT} = 100\text{ k}\Omega$

(Note 8) Voltage is measured from GND unless otherwise noted.

**Operation and Functionality**

The BD67870MWV-Z (gate driver device) is three-phase Brushless DC Motor gate driver that is capable of driving external N-channel MOSFET in half-bridge configuration with 0.5 A sourcing and 1 A sinking capability. The gate driver operates over a wide input voltage range of 4.5 V to 60 V while also supporting up to 100 % duty cycle output gate drive with trickle charge pump. A nominal gate drive voltage of 12.5 V allows operation of external N-channel MOSET for lower R<sub>DS(on)</sub> and lowering power losses. The gate drive features protection features such as input voltage under voltage lockout, gate driver power supply voltage under voltage lockout and internal thermal shutdown. Additionally, an adjustable dead time control circuit allows robust system operation.

**Timing Chart**

The timing chart of power up is shown in Figure 4, while power down is shown in Figure 5. Power-up sequence starts after the voltage on V<sub>CC</sub> is V<sub>CC</sub> UVLO threshold (V<sub>CC\_GOOD</sub>) or above. After this the gate driver power supply V<sub>REG</sub> starts to power-on. V<sub>REG</sub> voltage must be V<sub>REG</sub> UVLO (V<sub>REG\_GOOD</sub>) or above before the gate driver output is active and follow the input logic. When xSLEEP pin is pulled below the input logic low level, the chip will enter sleep mode. After this point the gate driver will stop to follow the input logic signal.

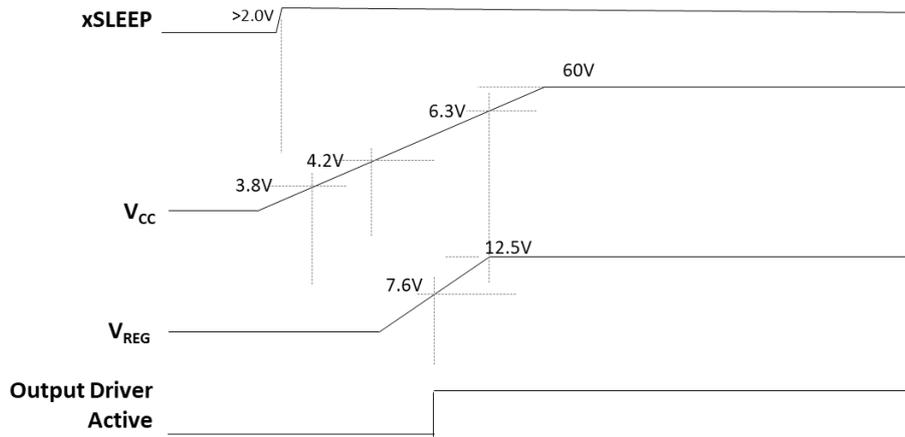


Figure 4. Timing Chart (power supply turn-on)

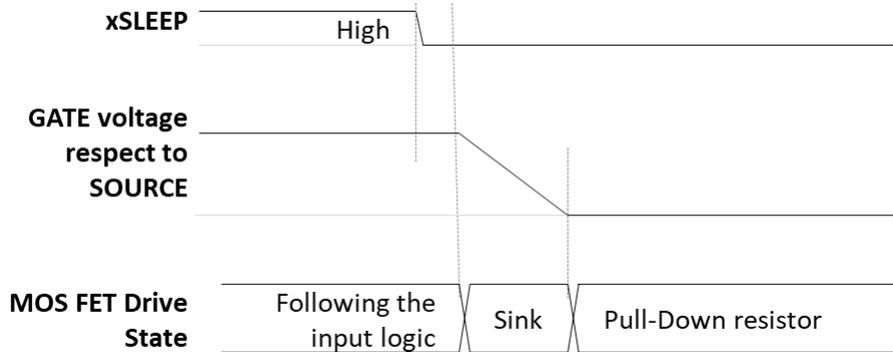


Figure 5. Timing Chart (xSLEEP pulled low)

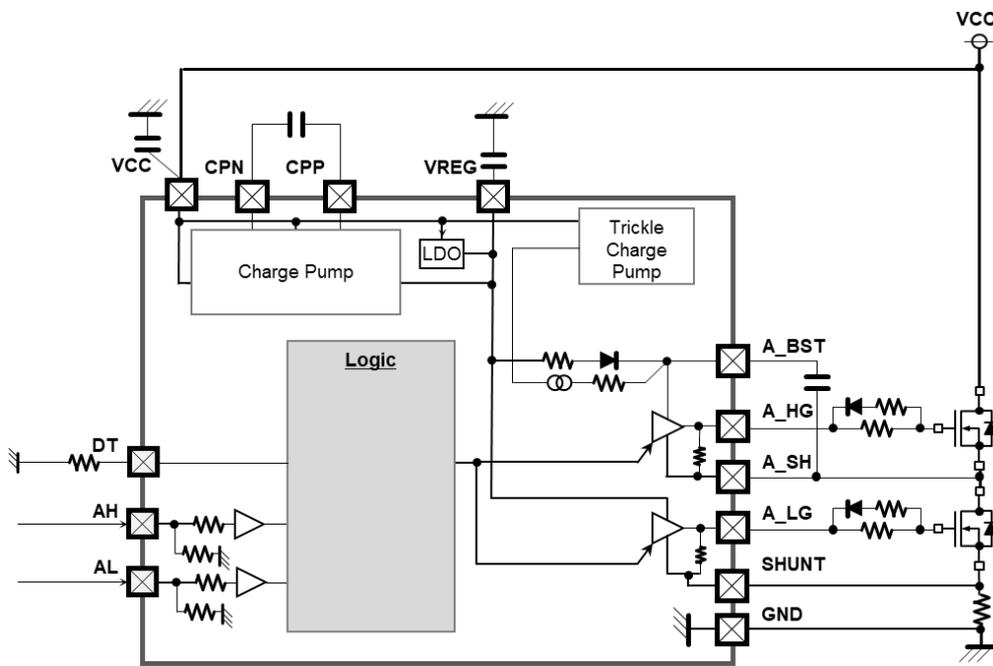
Operation and Functionality - continued

Gate Drive Architecture

The gate driver chip has both an internal high-side push-pull and an internal low-side push-pull driver to drive external N-channel MOSFETs. Input pin AH, BH, CH directly provide logic input signal for the high-side driver, while the AL, BL, CL pin provide logic input signal for the low-side driver.

The low-side driver is powered directly from the VREG pin and referenced to the SHUNT pin. The high-side driver on the other hand is powered by a bootstrap circuitry that includes an internal bootstrap diode and an external bootstrap capacitor. The bootstrap circuitry operates by taking power from VREG pin and, relying on the switching operation of the switching node, will create a floating supply between A\_BST, B\_BST, C\_BST and A\_SH, B\_SH, C\_SH pins. However, at very high output duty cycle operation there will not be enough off-time on the switching node to allow the bootstrap diode to recharge the external bootstrap capacitor thus causing the bootstrap capacitor to eventually lose charge. To circumvent this, an internal Current Source circuit is dedicated to always provide a small amount of charging current to the A\_BST, B\_BST, C\_BST pin directly from the VCC pin thus allowing external bootstrap capacitor to not discharge and allowing 100 % output duty cycle operation with trickle charge pump.

Additionally, both the high-side driver and the low-side driver includes an internal pulldown resistor between the gate pin and the return pin to ensure the external MOSFET is not accidentally turned on when the respective gate driver does not have sufficient power.



Above diagram only shows for Channel-A, but also applies for Channel-B and Channel-C

Figure 6. Gate Driver Architecture



## Operation and Functionality - continued

### Input Logic

Table 2 shows the input logic truth table for BD67870MWV-Z. In this version, the AH, BH, CH and AL, BL, CL input signals directly control the state of the A\_HG, B\_HG, C\_HG and A\_LG, B\_LG, C\_LG output drive signal as long as xSLEEP is high level. When AH, BH, CH and AL, BL, CL input signals are high level at the same time, the A\_HG, B\_HG, C\_HG and A\_LG, B\_LG, C\_LG output drive signals are forced low to prevent cross conduction of external N-channel MOSFET.

Table 2. BD67870MWV-Z Input Logic Truth Table (6x PWM Mode)

xSLEEP	AH (BH / CH)	AL (BL / CL)	A_HG (B_HG / C_HG)	A_LG (B_LG / C_LG)	A_SH (B_SH / C_SH)
0	X	X	L	L	Hi-Z
1	0	0	L	L	Hi-Z
1	0	1	L	H	GND
1	1	0	H	L	V <sub>cc</sub>
1	1	1	L	L	Hi-Z

### Cross Conduction Prevention

Input logic pins AH, BH, CH and AL, BL, CL is provided externally and controls the gate signal directly, there is a cross conduction prevention function that prevents both external N-channel MOSFET from turning on when both AH, BH, CH and AL, BL, CL input signals are a Table 2. BD67870MWV-Z will output both high-side drive signal A\_HG, B\_HG, C\_HG and low-side drive signal A\_LG, B\_LG, C\_LG to be low thus turning off .

### Dead Time Adjustment

BD67870MWV-Z have dead time adjustment control function to prevent both external N-channel MOSFET from accidentally turning on at the same time during switchover when turning on/off of the respective external N-channel MOSFET. The duration of the dead time can be adjusted by an external resistor connected to the DT pin and ground. The duration can be adjusted between 110 ns to 1800 ns by choosing a resistor between 3.3 kΩ to 100 kΩ (higher values should be avoided). The equation below shows the relationship between external resistor and the dead time duration. However, if an external resistor of 840 Ω or less is used, the dead time is 10 ns.(Figure 16) Please note that there are variations in ICs, so be careful when using resistors of 1 kΩ or less.

$$t_{DEAD} = 17.5 \times R_{DT} + 52 \quad (R_{DT} \geq 1 \text{ k}\Omega) \quad [\text{ns}]$$

Where:

$t_{DEAD}$  [ns] is the Dead time.

$R_{DT}$  [kΩ] is the Dead time adjustment resistor that connected to the DT pin and ground.

For example, to set a 1 μs dead time, a 54.2 kΩ resistor should be used.

To disable dead time (in the case that micro-controller can provide dead time itself), tie the DT pin to ground.

### Sleep Mode (xSLEEP input pin)

When the xSLEEP pin is driven to ground, the gate driver device is put into sleep mode and consumes little quiescent current in order to reduce power consumption from the input VCC pin. At this state, all the internal circuitry is disabled, and all the input logic pins are ignored. The gate driver output is put into high-impedance mode. When xSLEEP pin is driven high, the gate driver will start the power up sequence.

## Operation and Functionality - continued

### Protection

The BD67870MWV-Z has features to protect against input voltage  $V_{CC}$  under voltage lockout ( $V_{CC}$  UVLO), regulated driver voltage supply  $V_{REG}$  under voltage lockout ( $V_{REG}$  UVLO), and internal Thermal Shutdown (TSD).

For  $V_{CC}$  UVLO, the gate driver chip will turn off and all output drive voltages whenever the input voltage  $V_{CC}$  drops below  $V_{CC\_NG}$  threshold. The gate driver will recover and turn back on when input voltage  $V_{CC}$  rises above  $V_{CC\_GOOD}$ .

For both  $V_{REG}$  UVLO and TSD, the behavior of the output drive voltage, the xFAULT pin condition as well as the recovery method is shown in the table below.

Table 3. Behavior of  $V_{REG}$  UVLO and Internal Thermal Shutdown Protection Features

Fault	Condition	xFAULT	OUTPUT	Recovery
$V_{REG}$ UVLO	$V_{REG} \leq V_{REG\_NG}$	Pulled Low	Hi-Z	Auto / xSLEEP = L
	$V_{REG} \geq V_{REG\_GOOD}$	Hi-Z	Active	
Thermal Shutdown	Internal die temperature $\geq T_{TSDON}$	Pulled Low	Hi-Z	Auto / xSLEEP = L
	Internal die temperature $\leq T_{TSDOFF}$	Hi-Z	Active	

### xFAULT Pin

xFAULT indicates that a fault condition occurred in the gate driver chip. A pullup resistor to an externally supplied e.g. 5 V (depends on the Controller side input range) voltage is required to be connected to the xFAULT pin.

Normally xFAULT pin is in Hi-Z condition. If either an Under Voltage Lockout on  $V_{REG}$  voltage occurs, or a Thermal Shutdown (TSD) event occurs, the xFAULT pin on the device will be pulled low by an internal pulldown device. The xFAULT pin will only be pulled low during the duration of the fault condition.

### De-glitcher for FAULT Condition

A 3  $\mu$ s (Typ) de-glitching filter is employed to avoid any false detection of fault conditions that may be caused by noise conditions.

Application and Implementation Guide

Recommended External Components for Typical Application

Table 4. Recommended External Components  
 (\*) denotes "A/B/C"

Components	PIN 1	PIN 2	Recommended
VCC Bypass Bulk Capacitor	VCC	GND	$\geq 22 \mu\text{F}$ , $> 2 \times V_{\text{CC}}$ rated Bulk Capacitor
VCC Bypass Ceramic Capacitor	VCC	GND	$\geq 0.1 \mu\text{F}$ , $> 2 \times V_{\text{CC}}$ rated X5R or X7R Ceramic Capacitor
Charge Pump Capacitor	CPP	CPN	470 nF, $V_{\text{CC}}$ rated X5R or X7R Ceramic Capacitor
Regulator Bypass Capacitor	VREG	GND	$\geq 10 \mu\text{F}$ , $> 25 \text{ V}$ rated X5R or X7R Ceramic Capacitor
Pull up of xFAULT	xFAULT	$\leq 5.5 \text{ V}$	Pullup resistor for suitable voltage for the controller
Dead Time Adjust Resistor	DT	GND	Pulldown resistor
Gate Resistor	*_HG/ *_LG	Gate of MOS	Gate control resistor ( $\leq 10 \Omega$ )
Bootstrap Capacitor	*_BST	*_SH	Bootstrap capacitor

Application Example

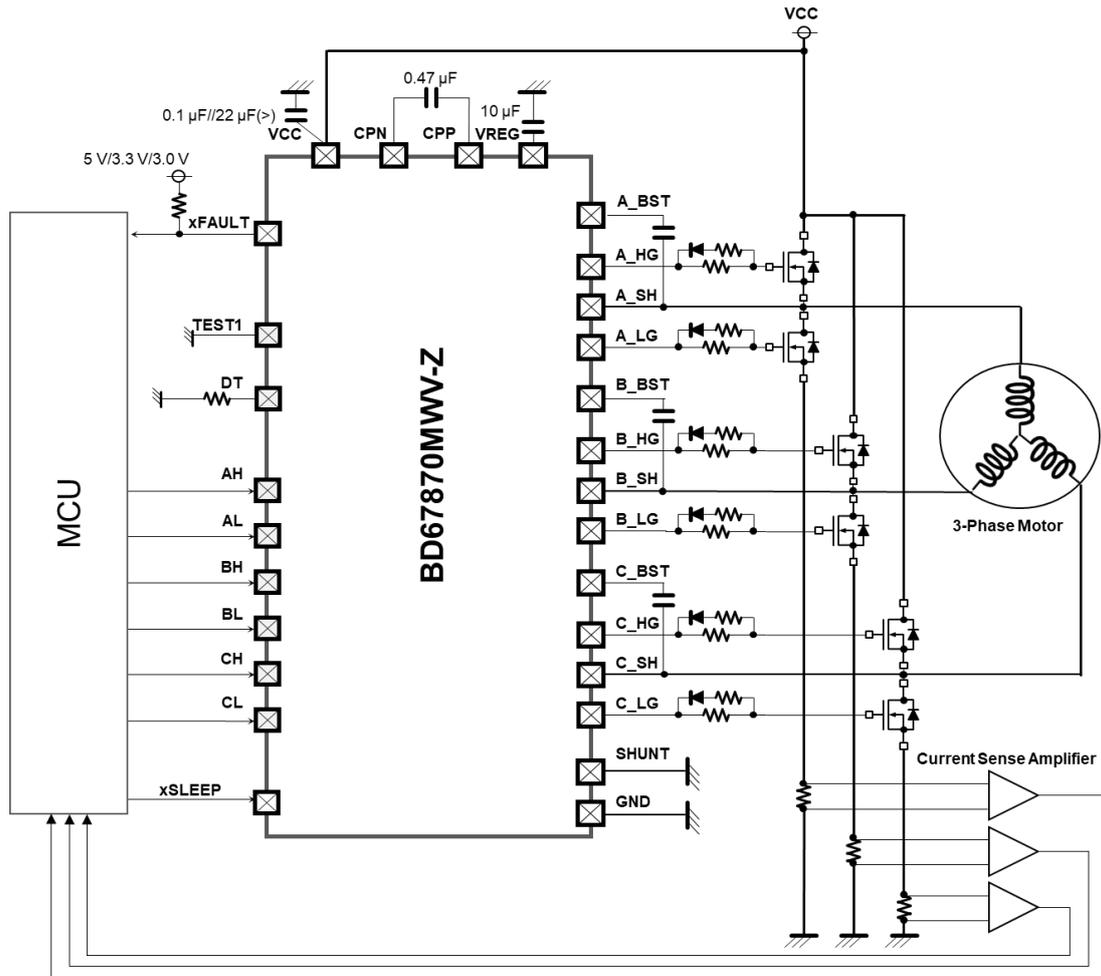


Figure 8. Application Example (Three Shunt)

## Application and Implementation Guide - continued

### Input Power Supply Capacitor Recommendation

Two types of capacitors are recommended to be used on input power supply line VCC. A electrolytic bulk capacitor 22  $\mu\text{F}$  or above that has voltage rating is  $2 \times V_{\text{CC}}$  or above voltage should be placed near the main connection point of the power supply. A ceramic capacitor (X5R or X7R) 0.1  $\mu\text{F}$  or above with voltage rating  $2 \times V_{\text{CC}}$  or above voltage should be placed in parallel to supply high frequency components. In addition, it is recommended to place similar ceramic capacitors in between the drain of each high-side MOSFET to the source of the low-side MOSFET for each leg of the 3 phase half-bridges.

### Bootstrap Capacitor and VREG Capacitor Calculation

Bootstrap Capacitor hold the electrical charge to drive the high-side MOSFET while it is turning on. The charge of the bootstrap capacitor will be used towards charging to high-side MOSFET gate capacitor. It is recommended to follow the below equation:

$$C_{\text{BOOST}} \geq 10 \times Qg \quad [\text{nF}]$$

Where:

$C_{\text{BOOST}}$  [nF] is the capacitance of the bootstrap capacitor.  
 $Qg$  [nC] is the total MOSFET gate charge.

For example, when the high-side MOSFET  $Qg = 100 \text{ nC}$ , select a bootstrap capacitor of value  $\geq 1 \mu\text{F}$  with a voltage rating  $\geq 2 \times V_{\text{REG}}$  (ie. 25 V). This Bootstrap capacitor is driven by current limiting driver, and it has an ability of Min 30 mA. It has to be considered about Bootstrap sequence time duration for enough charging up time.

VREG capacitor holds the charge to supply all of the high-side drivers and low-side drivers. The value should be larger than 6 times or above of the bootstrap capacitor. It is recommended to follow the below equation:

$$C_{\text{VREG}} \geq 6 \times C_{\text{BOOST}} \quad [\text{nF}]$$

Where:

$C_{\text{VREG}}$  [nF] is the capacitance of the VREG capacitor.

For example, when  $C_{\text{BOOST}} = 1 \mu\text{F}$ , then select the capacitor on  $V_{\text{REG}}$  is 6  $\mu\text{F}$  or above. However, we recommend 10  $\mu\text{F}$  for this because the actual capacitance value will be affected by DC biasing. Also select the VREG capacitor voltage rating to be 25 V or above. This VREG capacitor is driven by current limiting driver, depends on  $V_{\text{CC}}$  range (Please refer to Table 1)

Application and Implementation Guide - continued

Gate Resistor Guide for Suitable Gate Current Control

The BD67870MWV-Z is voltage mode gate drivers and includes a strong internal source and sink MOSFET which has low resistance. To limit the slew rate of the gate voltage, it is necessary to include a network of series gate resistor. The calculation of the series gate resistor depends on the total gate charge of the MOSFET being driver, the voltage of the gate driver power supply, the miller plateau voltage of the MOSFET as well as the desired slew rate of the gate voltage. The figure below shows a configuration where the turn-on is limited by series gate resistor R1, while the turn-off is a parallel combination of R1 and R2. This will create different turn-on and turn-off time.

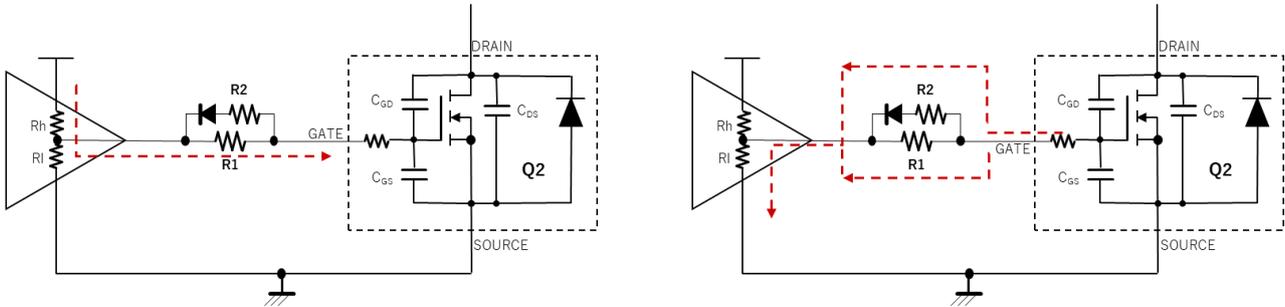


Figure 9. Gate Resistor Configuration for Asymmetrical Turn-on and Turn-off

Parallel MOSFET Configuration

For higher current applications, it may be necessary to connect MOSFET in parallel. For such designs, it is important to pay attention to certain aspect of circuit and PCB design. In particular, issues such as current crowding causing to one path heating up more than the other, and self-excited oscillations may occur.

The Figure 10 below shows parasitic components such as drain inductance, source inductance, and gate inductance that if not paid attention to may lead to self-excited oscillations. In general rule, all these inductances should be minimized by using thicker and shorter PCB paths. In addition, individual gate resistors should be used for each parallel MOSFET to ensure more symmetrical current flow.

Additionally, the value of bootstrap capacitor and VREG pin capacitor should be scaled up appropriately to take into account a larger total gate charge that the chip needs to drive.

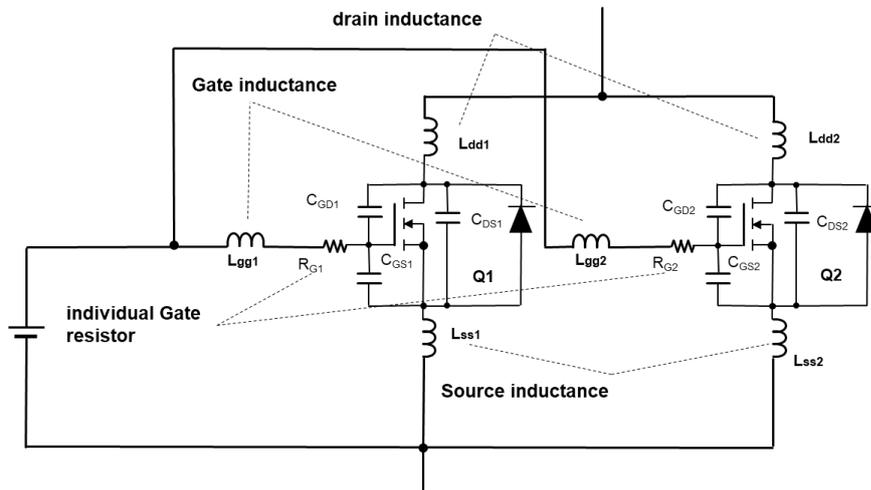


Figure 10. Parasitic Components when Designing for Parallel MOSFET Configuration

**PCB Layout Guidelines**

High current switching gate driver application require that PCB layout guidelines be followed to ensure optimal performance. In general, below are some important points to consider:

**Parasitic inductances should be minimized as they will cause unwanted voltage spikes due to high di/dt current slew rates. This is particularly important on the traces where switching currents operate: drain of power MOSFET, source of power MOSFET, and gate driver output connection to the MOSFET gate. To reduce parasitic PCB trace inductance, use wide copper traces for all the high switching current paths.**

1. Place all power supply capacitors (charge pump capacitors, input filter capacitor for VCC pin, capacitor on VREG pin) as close as possible to their respective pins. Route the ground side of the VCC and VREG capacitors to the GND pin of the gate driver device.
2. Separate the path for the input V<sub>CC</sub> voltage into the gate driver chip from the V<sub>CC</sub> voltage going to the 3 half-bridges. The path going to the half-bridges is a high current path and as such PCB trace should be wide and if possible connected on multiple layers. Place a bulk electrolytic capacitor near the VCC pin and also a local ceramic capacitors near to the high-side MOSFET drains.
3. Place the bootstrap capacitors for the high-side gate drivers as close as possible to the gate driver chip and when possible on the same layer as the gate driver chip to avoid any vias that introduce parasitic inductance.
4. Layout the high current paths from the VCC pin towards the 3 phases of the half-bridges and towards the return GND path symmetrically to avoid any current crowding and to allow each leg to flow current in a balanced manner.

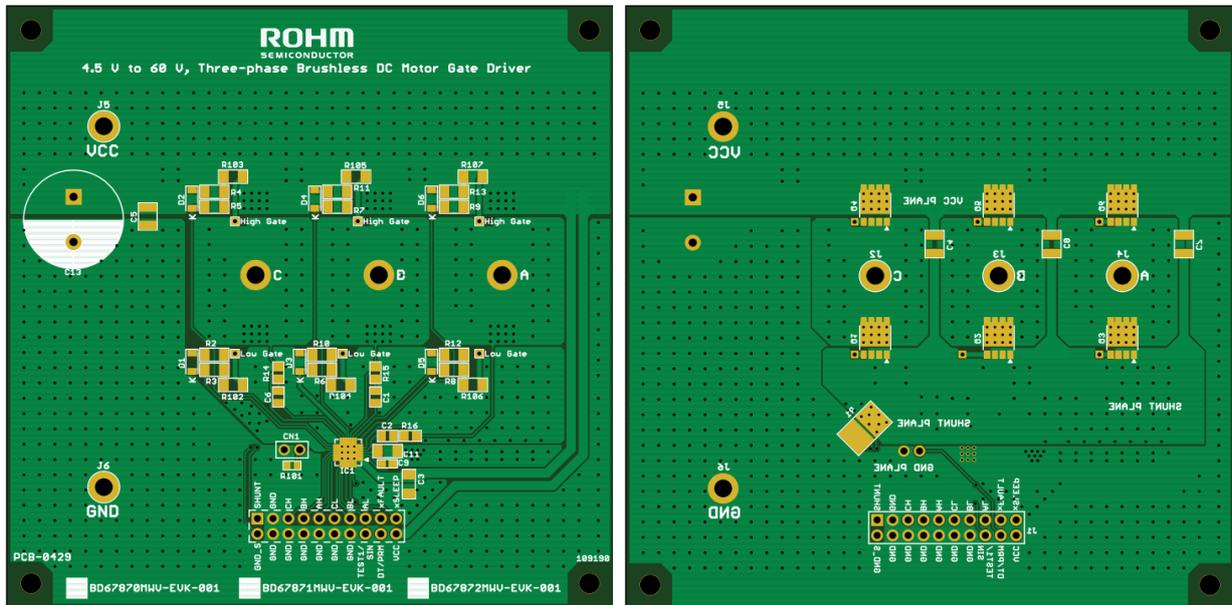


Figure 11. Top View of Recommended PCB Layout (100 mm x 100 mm)

Typical Performance Curves (Reference Data)

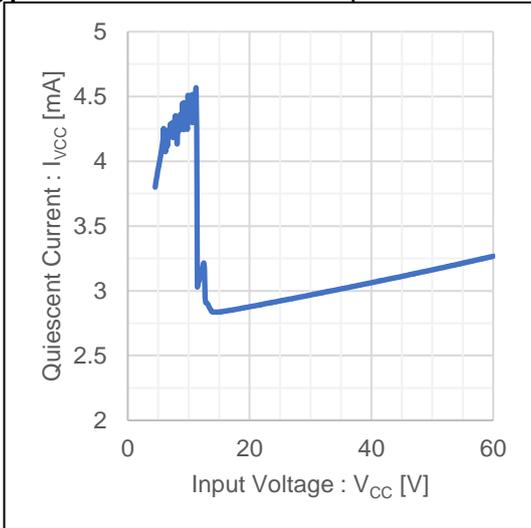


Figure 12. Quiescent Current vs Input Voltage

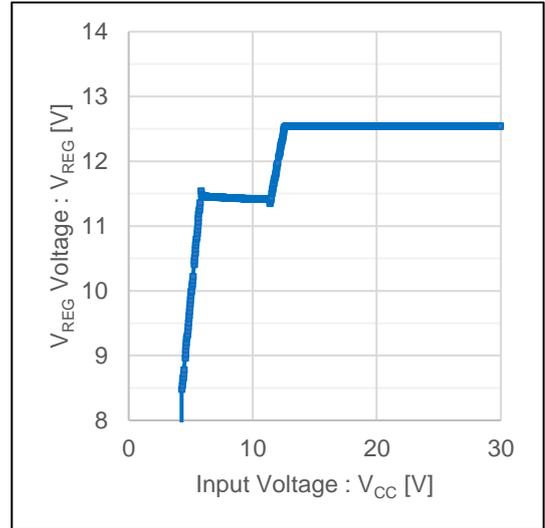


Figure 13.  $V_{REG}$  Voltage vs Input Voltage (No Load)

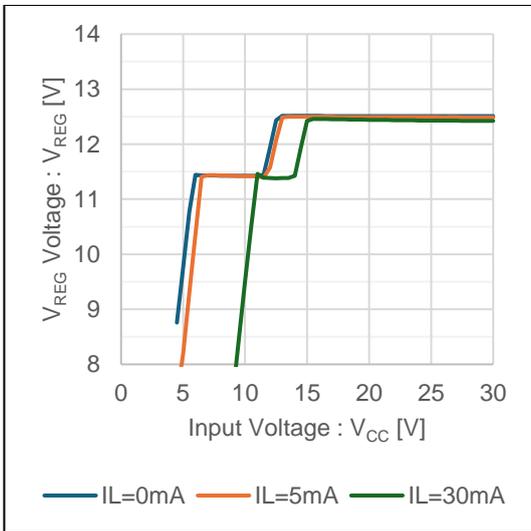


Figure 14.  $V_{REG}$  Voltage vs Input Voltage at Different Load Currents

Typical Performance Curves (Reference Data) - continued

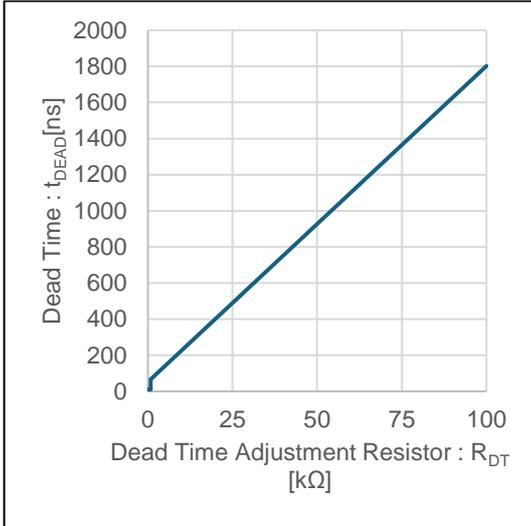


Figure 15. Dead Time vs Dead Time Adjustment Resistor

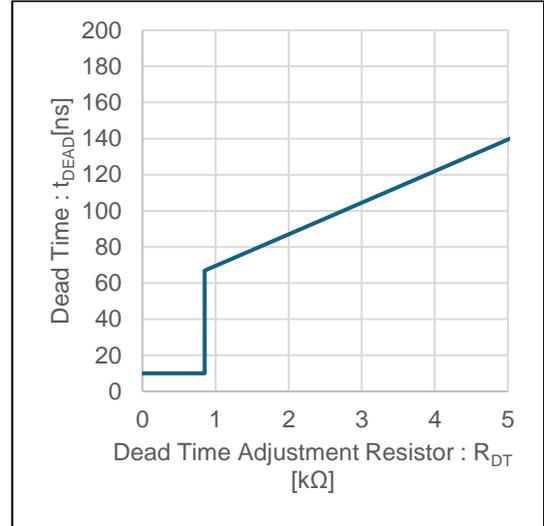


Figure 16. Dead Time vs Dead Time Adjustment Resistor (Zoom)

Characteristic Data (Reference Data)

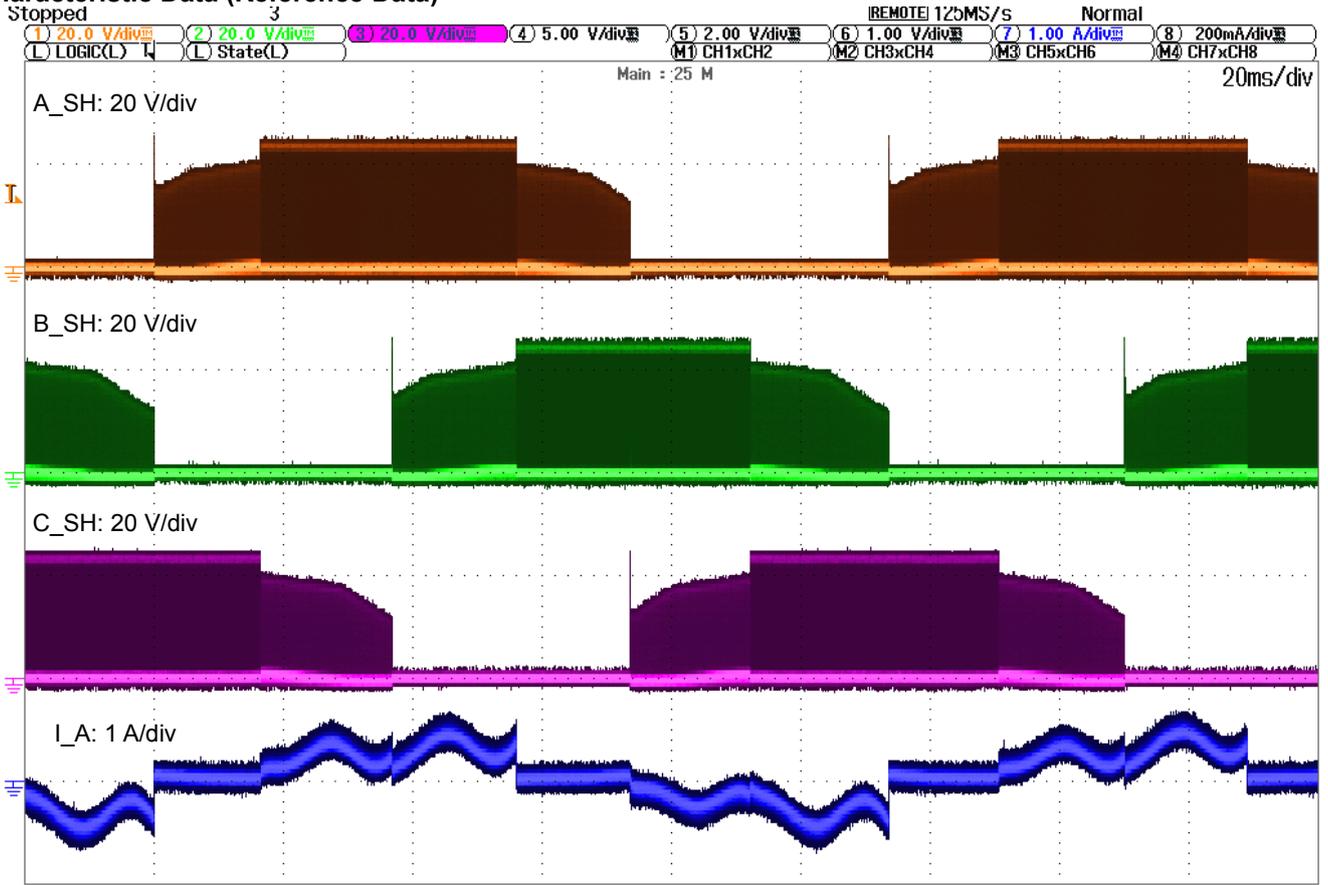


Figure 17. \*\_SH Waveform of Trapezoidal Motor Control  
(PWM frequency = 20 kHz, Dead Time = 3  $\mu$ s,  $V_{CC}$  = 24 V, Duty = 12.5 %)

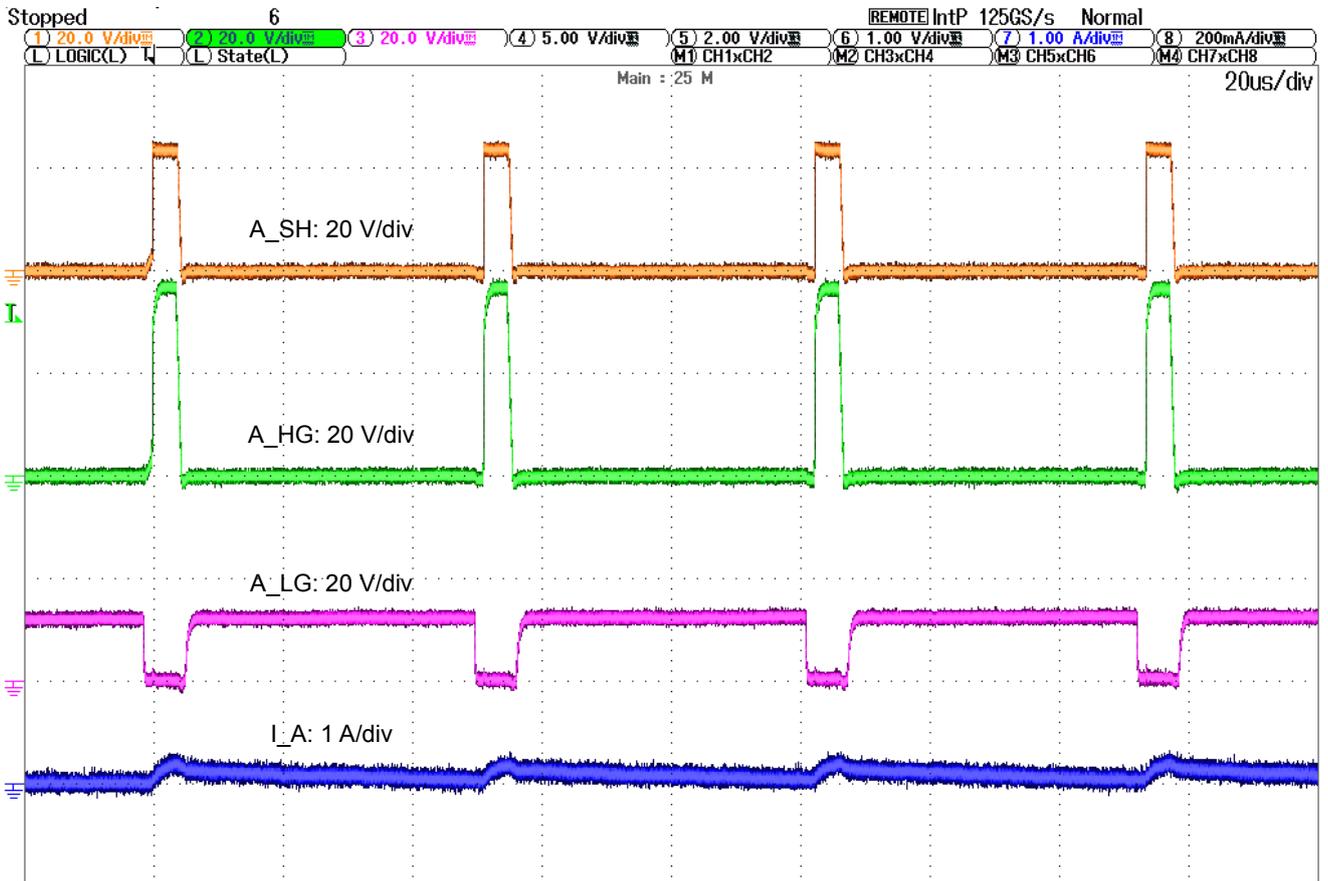


Figure 18. Gate Waveform of Trapezoidal Motor Control  
(PWM frequency = 20 kHz, Dead Time = 3  $\mu$ s,  $V_{CC}$  = 24 V, Duty = 12.5 %)

Characteristic Data (Reference Data) - continued

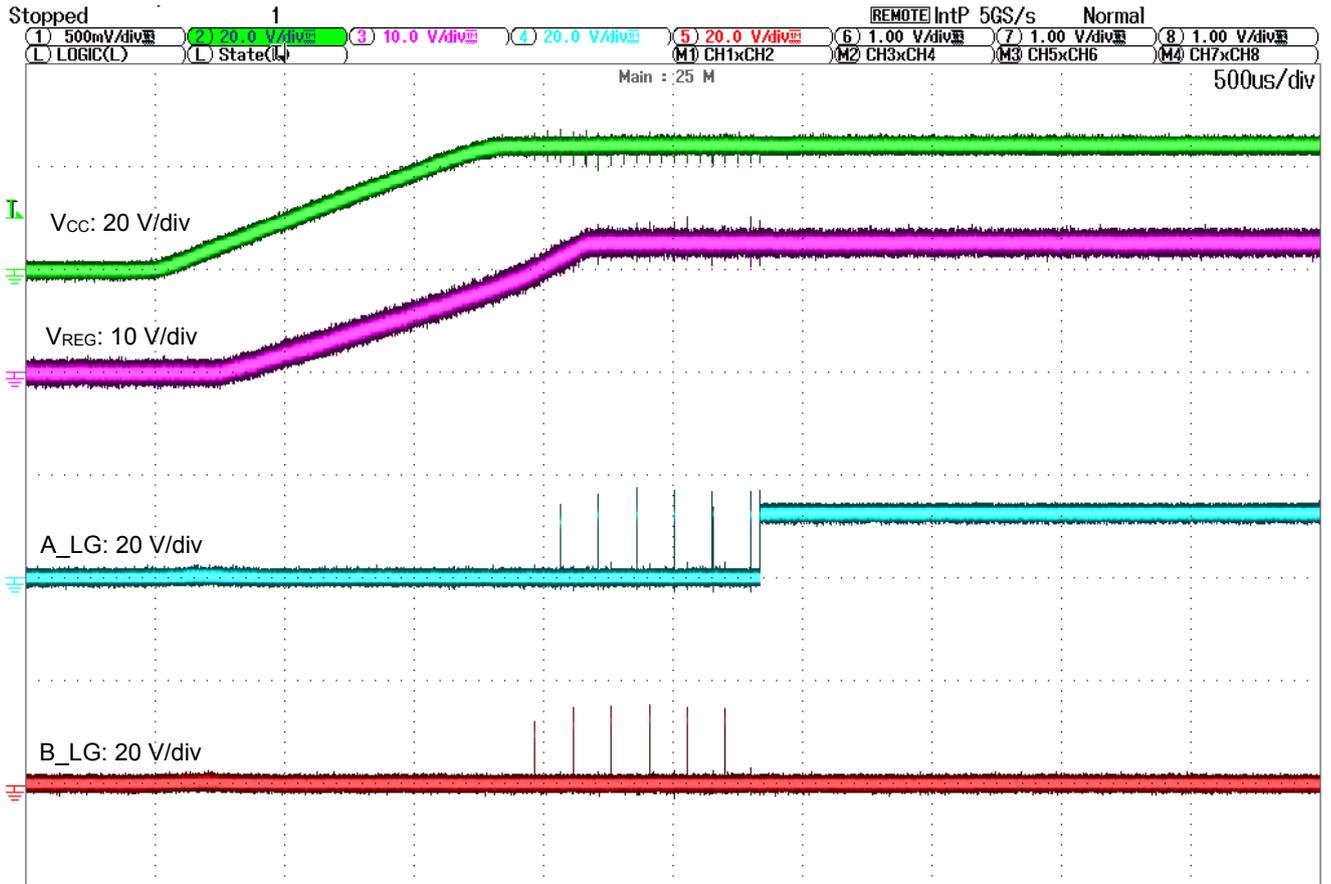


Figure 19. Start-up Sequence on Slow V<sub>CC</sub> Start up

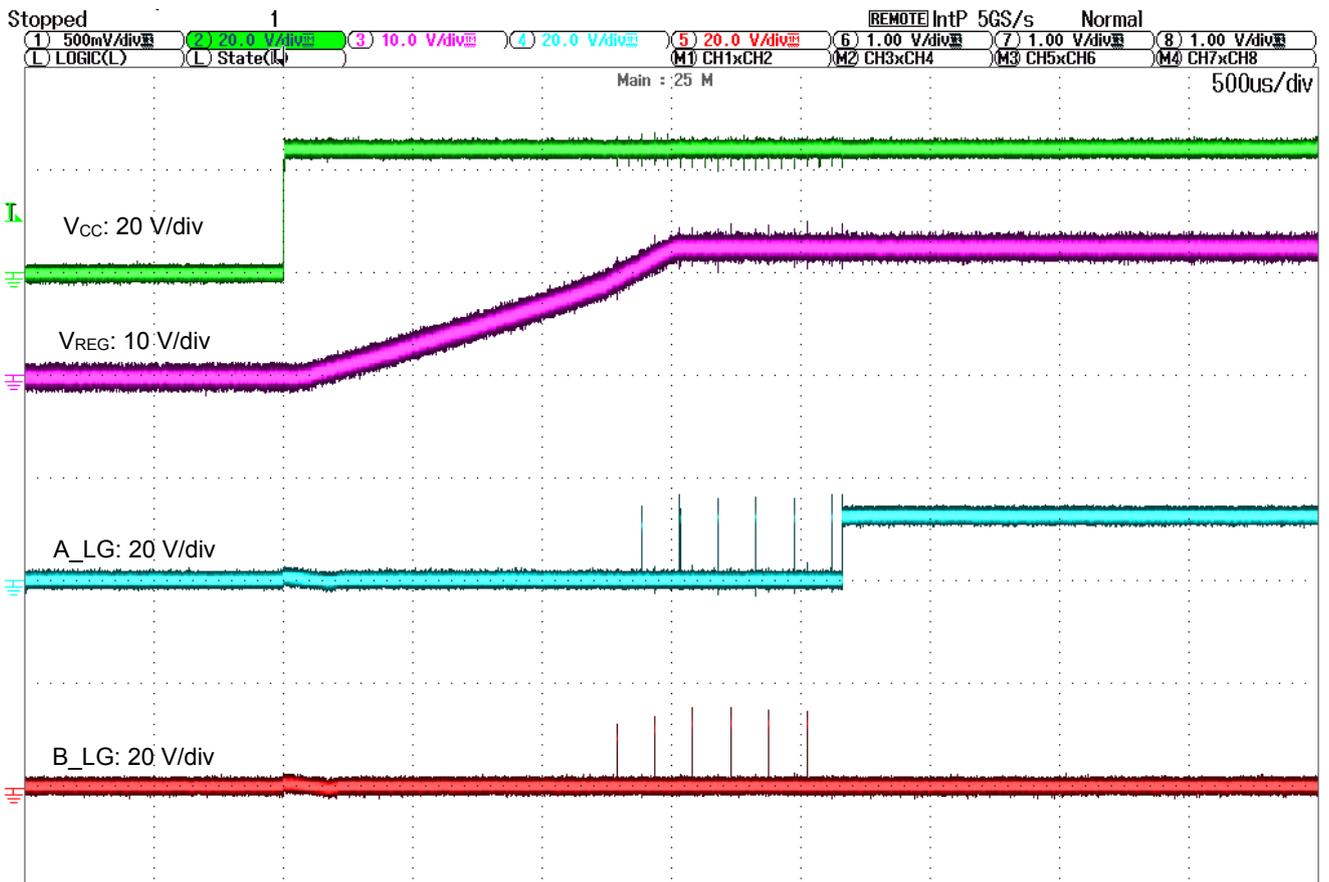


Figure 20. Start-up Sequence on Fast V<sub>CC</sub> Start up

Characteristic Data (Reference Data) - continued

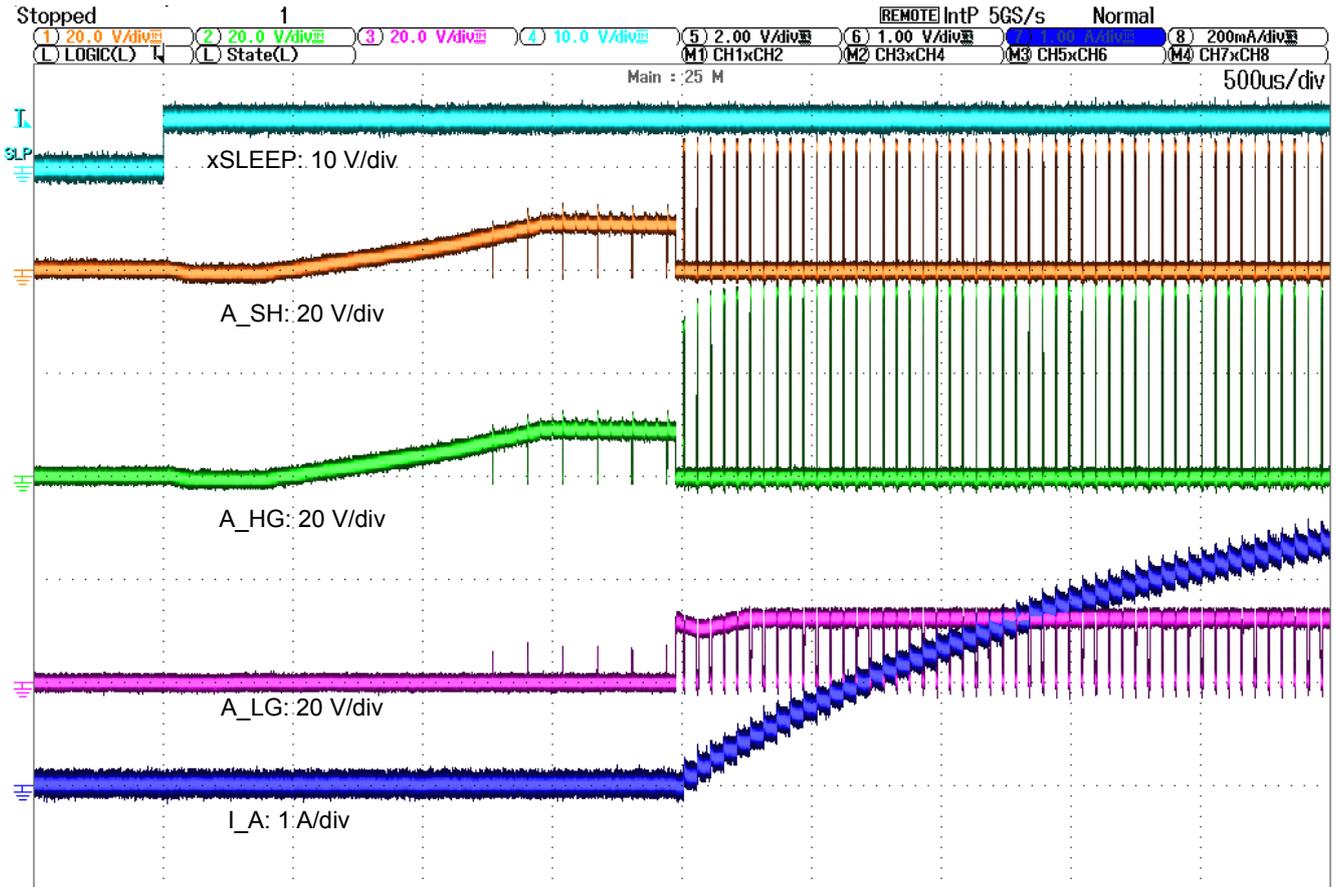


Figure 21. Sleep Recovery

## ESD Ratings

Item	Value	Unit
Human Body Model (HBM)	+/-2000	V
Charged Device Model (CDM)	+/-750	V

## Operational Notes

### 1. Reverse Connection of Power Supply

Connecting the power supply in reverse polarity can damage the IC. Take precautions against reverse polarity when connecting the power supply, such as mounting an external diode between the power supply and the IC's power supply pins.

### 2. Power Supply Lines

Design the PCB layout pattern to provide low impedance supply lines. Furthermore, connect a capacitor to ground at all power supply pins. Consider the effect of temperature and aging on the capacitance value when using electrolytic capacitors.

### 3. Ground Voltage

Except for pins the output and the input of which were designed to go below ground, ensure that no pins are at a voltage below that of the ground pin at any time, even during transient condition.

### 4. Ground Wiring Pattern

When using both small-signal and large-current ground traces, the two ground traces should be routed separately but connected to a single ground at the reference point of the application board to avoid fluctuations in the small-signal ground caused by large currents. Also ensure that the ground traces of external components do not cause variations on the ground voltage. The ground lines must be as short and thick as possible to reduce line impedance.

### 5. Recommended Operating Conditions

The function and operation of the IC are guaranteed within the range specified by the recommended operating conditions. The characteristic values are guaranteed only under the conditions of each item specified by the electrical characteristics.

### 6. Inrush Current

When power is first supplied to the IC, it is possible that the internal logic may be unstable and inrush current may flow instantaneously due to the internal powering sequence and delays, especially if the IC has more than one power supply. Therefore, give special consideration to power coupling capacitance, power wiring, width of ground wiring, and routing of connections.

### 7. Testing on Application Boards

When testing the IC on an application board, connecting a capacitor directly to a low-impedance output pin may subject the IC to stress. Always discharge capacitors completely after each process or step. The IC's power supply should always be turned off completely before connecting or removing it from the test setup during the inspection process. To prevent damage from static discharge, ground the IC during assembly and use similar precautions during transport and storage.

## Operational Notes – continued

**8. Inter-pin Short and Mounting Errors**

Ensure that the direction and position are correct when mounting the IC on the PCB. Incorrect mounting may result in damaging the IC. Avoid nearby pins being shorted to each other especially to ground, power supply and output pin. Inter-pin shorts could be due to many reasons such as metal particles, water droplets (in very humid environment) and unintentional solder bridge deposited in between pins during assembly to name a few.

**9. Unused Input Pins**

Input pins of an IC are often connected to the gate of a MOS transistor. The gate has extremely high impedance and extremely low capacitance. If left unconnected, the electric field from the outside can easily charge it. The small charge acquired in this way is enough to produce a significant effect on the conduction through the transistor and cause unexpected operation of the IC. So unless otherwise specified, unused input pins should be connected to the power supply or ground line.

**10. Regarding the Input Pin of the IC**

This monolithic IC contains P+ isolation and P substrate layers between adjacent elements in order to keep them isolated. P-N junctions are formed at the intersection of the P layers with the N layers of other elements, creating a parasitic diode or transistor. For example (refer to figure below):

When  $GND > Pin A$  and  $GND > Pin B$ , the P-N junction operates as a parasitic diode.

When  $GND > Pin B$ , the P-N junction operates as a parasitic transistor.

Parasitic diodes inevitably occur in the structure of the IC. The operation of parasitic diodes can result in mutual interference among circuits, operational faults, or physical damage. Therefore, conditions that cause these diodes to operate, such as applying a voltage lower than the GND voltage to an input pin (and thus to the P substrate) should be avoided.

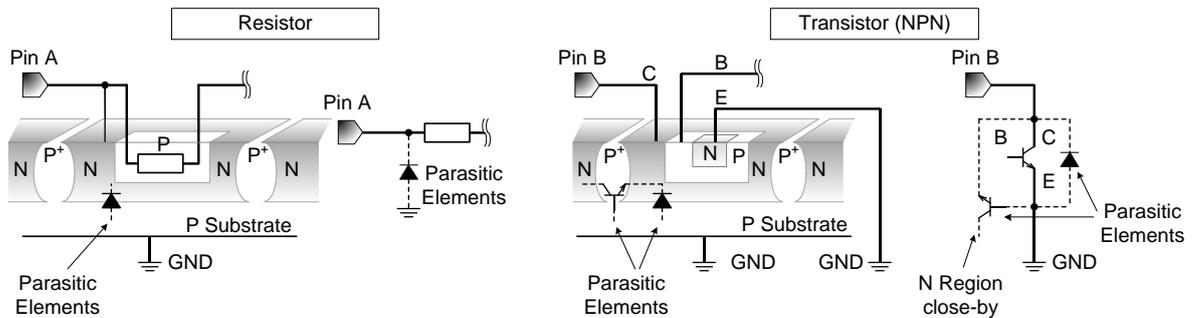


Figure 22. Example of Monolithic IC Structure

**11. Ceramic Capacitor**

When using a ceramic capacitor, determine a capacitance value considering the change of capacitance with temperature and the decrease in nominal capacitance due to DC bias and others.

**12. Thermal Shutdown Circuit (TSD)**

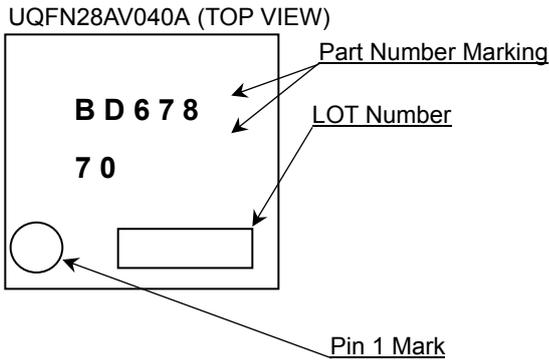
This IC has a built-in thermal shutdown circuit that prevents heat damage to the IC. Normal operation should always be within the IC's maximum junction temperature rating. If however the rating is exceeded for a continued period, the junction temperature ( $T_j$ ) will rise which will activate the TSD circuit that will turn OFF power output pins. When the  $T_j$  falls below the TSD threshold, the circuits are automatically restored to normal operation.

Note that the TSD circuit operates in a situation that exceeds the absolute maximum ratings and therefore, under no circumstances, should the TSD circuit be used in a set design or for any purpose other than protecting the IC from heat damage.

Ordering Information

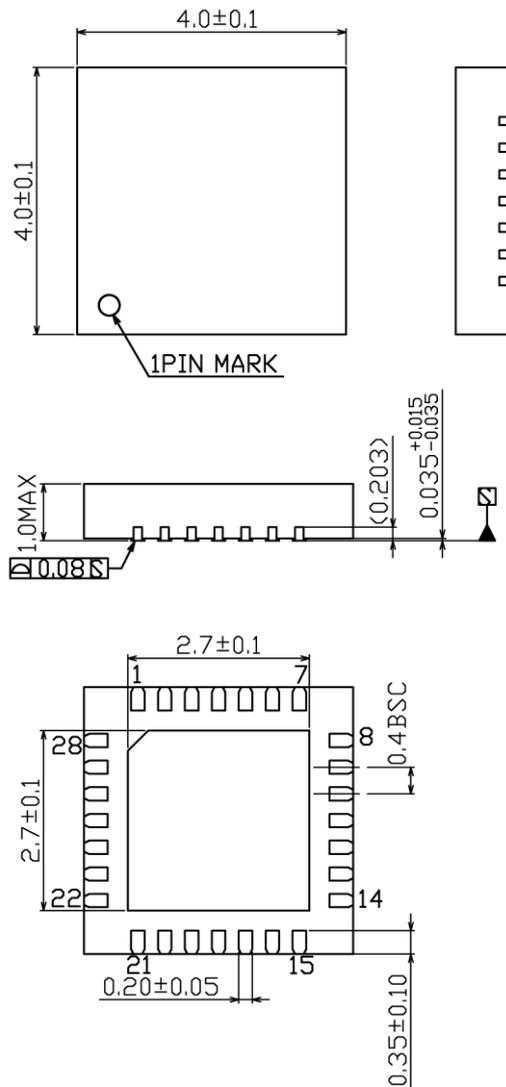


Marking Diagram



Physical Dimension and Packing Information

Package Name	UQFN28AV040A
--------------	--------------

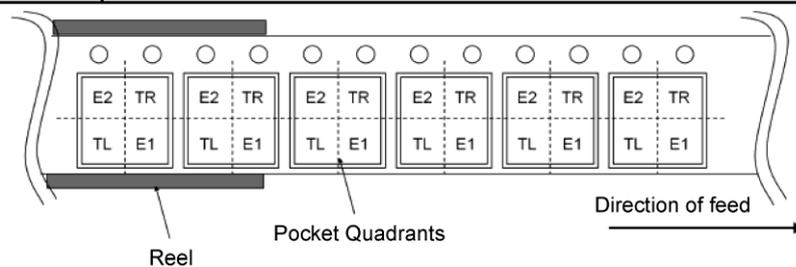


(UNIT:mm)

PKG:UQFN28AV040A  
Drawing No.EX001-0129

< Tape and Reel Information >

Tape	Embossed carrier tape
Quantity	2500pcs
Direction of feed	E2 The direction is the pin 1 of product is at the upper left when you hold reel on the left hand and you pull out the tape on the right hand



**Revision History**

Date	Revision	Changes
29.Jan.2025	001	New Release

# Notice

## Precaution on using ROHM Products

- Our Products are designed and manufactured for application in ordinary electronic equipment (such as AV equipment, OA equipment, telecommunication equipment, home electronic appliances, amusement equipment, etc.). If you intend to use our Products in devices requiring extremely high reliability (such as medical equipment <sup>(Note 1)</sup>, transport equipment, traffic equipment, aircraft/spacecraft, nuclear power controllers, fuel controllers, car equipment including car accessories, safety devices, etc.) and whose malfunction or failure may cause loss of human life, bodily injury or serious damage to property ("Specific Applications"), please consult with the ROHM sales representative in advance. Unless otherwise agreed in writing by ROHM in advance, ROHM shall not be in any way responsible or liable for any damages, expenses or losses incurred by you or third parties arising from the use of any ROHM's Products for Specific Applications.

(Note1) Medical Equipment Classification of the Specific Applications

JAPAN	USA	EU	CHINA
CLASS III	CLASS III	CLASS II b	CLASS III
CLASS IV		CLASS III	

- ROHM designs and manufactures its Products subject to strict quality control system. However, semiconductor products can fail or malfunction at a certain rate. Please be sure to implement, at your own responsibilities, adequate safety measures including but not limited to fail-safe design against the physical injury, damage to any property, which a failure or malfunction of our Products may cause. The following are examples of safety measures:
  - Installation of protection circuits or other protective devices to improve system safety
  - Installation of redundant circuits to reduce the impact of single or multiple circuit failure
- Our Products are designed and manufactured for use under standard conditions and not under any special or extraordinary environments or conditions, as exemplified below. Accordingly, ROHM shall not be in any way responsible or liable for any damages, expenses or losses arising from the use of any ROHM's Products under any special or extraordinary environments or conditions. If you intend to use our Products under any special or extraordinary environments or conditions (as exemplified below), your independent verification and confirmation of product performance, reliability, etc. prior to use, must be necessary:
  - Use of our Products in any types of liquid, including water, oils, chemicals, and organic solvents
  - Use of our Products outdoors or in places where the Products are exposed to direct sunlight or dust
  - Use of our Products in places where the Products are exposed to sea wind or corrosive gases, including Cl<sub>2</sub>, H<sub>2</sub>S, NH<sub>3</sub>, SO<sub>2</sub>, and NO<sub>2</sub>
  - Use of our Products in places where the Products are exposed to static electricity or electromagnetic waves
  - Use of our Products in proximity to heat-producing components, plastic cords, or other flammable items
  - Sealing or coating our Products with resin or other coating materials
  - Use of our Products without cleaning residue of flux (Exclude cases where no-clean type fluxes is used. However, recommend sufficiently about the residue.) ; or Washing our Products by using water or water-soluble cleaning agents for cleaning residue after soldering
  - Use of the Products in places subject to dew condensation
- The Products are not subject to radiation-proof design.
- Please verify and confirm characteristics of the final or mounted products in using the Products.
- In particular, if a transient load (a large amount of load applied in a short period of time, such as pulse, is applied, confirmation of performance characteristics after on-board mounting is strongly recommended. Avoid applying power exceeding normal rated power; exceeding the power rating under steady-state loading condition may negatively affect product performance and reliability.
- De-rate Power Dissipation depending on ambient temperature. When used in sealed area, confirm that it is the use in the range that does not exceed the maximum junction temperature.
- Confirm that operation temperature is within the specified range described in the product specification.
- ROHM shall not be in any way responsible or liable for failure induced under deviant condition from what is defined in this document.

## Precaution for Mounting / Circuit board design

- When a highly active halogenous (chlorine, bromine, etc.) flux is used, the residue of flux may negatively affect product performance and reliability.
- In principle, the reflow soldering method must be used on a surface-mount products, the flow soldering method must be used on a through hole mount products. If the flow soldering method is preferred on a surface-mount products, please consult with the ROHM representative in advance.

For details, please refer to ROHM Mounting specification

### Precautions Regarding Application Examples and External Circuits

1. If change is made to the constant of an external circuit, please allow a sufficient margin considering variations of the characteristics of the Products and external components, including transient characteristics, as well as static characteristics.
2. You agree that application notes, reference designs, and associated data and information contained in this document are presented only as guidance for Products use. Therefore, in case you use such information, you are solely responsible for it and you must exercise your own independent verification and judgment in the use of such information contained in this document. ROHM shall not be in any way responsible or liable for any damages, expenses or losses incurred by you or third parties arising from the use of such information.

### Precaution for Electrostatic

This Product is electrostatic sensitive product, which may be damaged due to electrostatic discharge. Please take proper caution in your manufacturing process and storage so that voltage exceeding the Products maximum rating will not be applied to Products. Please take special care under dry condition (e.g. Grounding of human body / equipment / solder iron, isolation from charged objects, setting of Ionizer, friction prevention and temperature / humidity control).

### Precaution for Storage / Transportation

1. Product performance and soldered connections may deteriorate if the Products are stored in the places where:
  - [a] the Products are exposed to sea winds or corrosive gases, including Cl<sub>2</sub>, H<sub>2</sub>S, NH<sub>3</sub>, SO<sub>2</sub>, and NO<sub>2</sub>
  - [b] the temperature or humidity exceeds those recommended by ROHM
  - [c] the Products are exposed to direct sunshine or condensation
  - [d] the Products are exposed to high Electrostatic
2. Even under ROHM recommended storage condition, solderability of products out of recommended storage time period may be degraded. It is strongly recommended to confirm solderability before using Products of which storage time is exceeding the recommended storage time period.
3. Store / transport cartons in the correct direction, which is indicated on a carton with a symbol. Otherwise bent leads may occur due to excessive stress applied when dropping of a carton.
4. Use Products within the specified time after opening a humidity barrier bag. Baking is required before using Products of which storage time is exceeding the recommended storage time period.

### Precaution for Product Label

A two-dimensional barcode printed on ROHM Products label is for ROHM's internal use only.

### Precaution for Disposition

When disposing Products please dispose them properly using an authorized industry waste company.

### Precaution for Foreign Exchange and Foreign Trade act

Since concerned goods might be fallen under listed items of export control prescribed by Foreign exchange and Foreign trade act, please consult with ROHM in case of export.

### Precaution Regarding Intellectual Property Rights

1. All information and data including but not limited to application example contained in this document is for reference only. ROHM does not warrant that foregoing information or data will not infringe any intellectual property rights or any other rights of any third party regarding such information or data.
2. ROHM shall not have any obligations where the claims, actions or demands arising from the combination of the Products with other articles such as components, circuits, systems or external equipment (including software).
3. No license, expressly or implied, is granted hereby under any intellectual property rights or other rights of ROHM or any third parties with respect to the Products or the information contained in this document. Provided, however, that ROHM will not assert its intellectual property rights or other rights against you or your customers to the extent necessary to manufacture or sell products containing the Products, subject to the terms and conditions herein.

### Other Precaution

1. This document may not be reprinted or reproduced, in whole or in part, without prior written consent of ROHM.
2. The Products may not be disassembled, converted, modified, reproduced or otherwise changed without prior written consent of ROHM.
3. In no event shall you use in any way whatsoever the Products and the related technical information contained in the Products or this document for any military purposes, including but not limited to, the development of mass-destruction weapons.
4. The proper names of companies or products described in this document are trademarks or registered trademarks of ROHM, its affiliated companies or third parties.

### General Precaution

1. Before you use our Products, you are requested to carefully read this document and fully understand its contents. ROHM shall not be in any way responsible or liable for failure, malfunction or accident arising from the use of any ROHM's Products against warning, caution or note contained in this document.
2. All information contained in this document is current as of the issuing date and subject to change without any prior notice. Before purchasing or using ROHM's Products, please confirm the latest information with a ROHM sales representative.
3. The information contained in this document is provided on an "as is" basis and ROHM does not warrant that all information contained in this document is accurate and/or error-free. ROHM shall not be in any way responsible or liable for any damages, expenses or losses incurred by you or third parties resulting from inaccuracy or errors of or concerning such information.